

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/746,514	JAGANNATHARAO ET AL.	
Examiner	Art Unit		2662	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5,970,067	10-1999	Sathe et al.	370/394
B	US-5,764,637	06-1998	Nishihara, Motoo	370/397
C	US-5,608,733	03-1997	Vallee et al.	370/394
D	US-6,198,754 B1	03-2001	Nakayama, Mikio	370/536
E	US-6,148,010	11-2000	Sutton et al.	370/536
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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Application/Control No.
09/746,514

Applicant(s)/Patent Under
Réexamination
JAGANNATHARAO ET AL.

Examiner
David Odland

Art Unit
2662

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5,764,637	06-1998	Nishihara, Motoo	370/397
B	US-6,449,658 B1	09-2002	Lafe et al.	709/247
C	US-5,448,572	09-1995	Knox et al.	370/228
D	US-6,549,522 B1	04-2003	Flynn, Jason Stuart	370/313
E	US-6,411,701 B1	06-2002	Stademann, Rainer	379/221.03
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
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